

STN	Nedeštruktívne skúšanie Zariadenia na skúšanie vírivými prúdmi Charakteristiky array snímačov a ich overovanie (ISO 20339: 2017)	STN EN ISO 20339 01 5018
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Non-destructive testing - Equipment for eddy current examination - Array probe characteristics and verification (ISO 20339:2017)

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

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EUROPEAN STANDARD
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English Version

**Non-destructive testing - Equipment for eddy current
examination - Array probe characteristics and verification
(ISO 20339:2017)**

Essais non destructifs - Appareillage pour examen par
courants de Foucault - Caractéristiques des capteurs
multiéléments et vérifications (ISO 20339:2017)

Zerstörungsfreie Prüfung - Technische Ausrüstung für
die Wirbelstromprüfung - Kenngrößen von
Sensorarrays und deren Verifizierung (ISO
20339:2017)

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European foreword

This document (EN ISO 20339:2017) has been prepared by Technical Committee ISO/TC 135 "Non-destructive testing" in collaboration with Technical Committee CEN/TC 138 "Non-destructive testing" the secretariat of which is held by AFNOR.

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Non-destructive testing — Equipment for eddy current examination — Array probe characteristics and verification

*Essais non destructifs — Appareillage pour examen par courants
de Foucault — Caractéristiques des capteurs multiéléments et
vérifications*





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Foreword

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This document was prepared by Technical Committee ISO/TC 135, *Non-destructive testing*, Subcommittee SC 4, *Eddy current testing*.

Non-destructive testing — Equipment for eddy current examination — Array probe characteristics and verification

1 Scope

This document identifies the functional characteristics of eddy current array probes and their interconnecting elements and provides methods for their measurement and verification.

The evaluation of these characteristics permits a well-defined description and comparability of eddy current array probes.

Where relevant, this document gives recommendations for acceptance criteria for the characteristics.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 12718, *Non-destructive testing — Eddy current testing — Vocabulary*

ISO 15548-1, *Non-destructive testing — Equipment for eddy current examination — Part 1: Instrument characteristics and verification*

ISO 15548-2:2013, *Non-destructive testing — Equipment for eddy current examination — Part 2: Probe characteristics and verification*

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